## Search Notes

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Application/Control No.	Applicant(s)/Patent Under Reexamination	
10585744	BANDOH ET AL.	
Examiner	Art Unit	
SELIM AHMED	2826	

SEARCHED				
Class	Subclass	Date	Examiner	
257	101, 102, 103, e33.033, e33.034	5/4/2009	/sa/	
	Updated search	11/13/2009	/sa/	
257	79, 13	6/18/2010	/sa/	
438	46, 47	6/18/2010	/sa/	
	Updated search	6/18/2010	/sa/	

SEARCH NOTES		
Search Notes	Date	Examiner
East Text search such as, Group III nitride, III-V nitride compound, GaN, n-type, layer/structure/film/region, high concentration, low concentration, Ge doped, pits/holes/recess, dislocation and their boolean combinations were searched. Please see attached search history.	5/4/2009	/sa/
Updated search	11/13/2009	/sa/
Updated search	6/18/2010	/sa/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
257	102, 103	6/18/2010	/sa/

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